

Abstract

Method for the optical inspection of a transparent protective layer
and of a colored patterned surface

5 With a method for the optical inspection of a transparent protective layer (14)
and of a colored patterned surface, whereby the transparent protective layer (14) at
least partially covers the colored patterned surface, and a first source of
illumination (40) and an imaging sensor (42) associated with the first source of
illumination (40) are provided, the protective layer (14) is illuminated with the
10 light emitted by the source of illumination (40) in order to recognize defective
places (30) inside and beneath the transparent protective layer (14). The first
source of illumination (40) emits light in the shortwaved visible range and the
light striking the surface penetrates at least partially into the protective layer (14)
and is scattered at the defective places (30). Light scattered back from the
15 defective places (30) is picked up by the imaging sensor (42) and the defective
places (30) are recognized by the local increase in the intensity of the light picked
up by the imaging sensor (42) in the area of the defective places (30).

(Figure 3)